



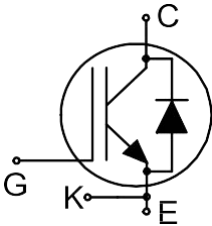
Features

- High Current Capability
- Low Saturation Voltage V_{CEsat}
- Low Switching Losses
- Copacked with Fast Recovery Diode



Benefits

- Low Conduction Loss for a High Efficiency
- Rugged Transient Reliability
- Low EMI



Applications

- UPS
- EV-Charging
- String Solar Inverter
- Energy Storage Inverter

Table 1 Key Performance and Package Parameters

Type	V_{CE}	I_c	V_{CEsat} $T_{vj} = 25^{\circ}C$ $I_c = 75A$	V_F $T_{vj} = 25^{\circ}C$ $I_F = 75A$	Package	Packing
IGBT	1200V	75A	1.91V	1.80V	TO-247P-4L	30PCS



Table 2 Absolute Maximum Ratings

($T_{vj} = 25^{\circ}\text{C}$ unless otherwise noted)

Parameters	Symbol	Conditions	Values	Unit
Collector emitter voltage	V _{CE}	T _{vj} = 25 °C	1200	V
DC collector current* ¹	I _C	T _C = 25 °C	100	A
		T _C = 100 °C	75	A
Pulsed collector current* ²	I _{CM}	T _C = 25 °C	300	A
Maximum Diode forward current* ¹	I _F	T _C = 25 °C	100	A
		T _C = 100 °C	75	A
Diode pulsed current* ²	I _{FM}	T _C = 25 °C	300	A
Gate source voltage	V _{GE}	T _{vj} = 25 °C	±20	V
Transient gate-emitter Voltage (tp ≤ 10μs, D < 0.010)	V _{GE}		±25	V
Power dissipation	P _{tot}	T _C = 25 °C	930	W
		T _C = 100 °C	460	
Operating junction temperature range	T _{vj}	-40 to +175		℃
Storage temperature range	T _{stg}	-55 to +150		

Notes:

1. The max Collector current rating is limited by maximum junction temperature
2. Pulse width limited by maximum junction temperature

Table 3 Thermal Resistance

Parameters	Symbol	Conditions	Values	Unit
IGBT thermal resistance junction - case	R_{thJC}	IGBT	0.16	K/W
Diode thermal resistance junction - case	R_{thJC}	Diode	0.33	K/W
Thermal resistance junction - ambient	R_{thJA}		40	K/W



Table 4 Static Characteristics

Parameters	Symbol	Conditions	Min	Typ	Max	Unit
Collector-emitter voltage	$V_{(BR)CES}$	$T_{vj} = 25\text{ }^{\circ}\text{C}$	1200	-	-	V
Collector-emitter saturation voltage	V_{CEsat}	$V_{GE} = 15\text{ V}, I_C = 75\text{ A}$ $T_{vj} = 25\text{ }^{\circ}\text{C}$	-	1.91	2.35	V
		$V_{GE} = 15\text{ V}, I_C = 75\text{ A}$ $T_{vj} = 175\text{ }^{\circ}\text{C}$	-	2.79	-	
Diode forward voltage	V_F	$V_{GE} = 0\text{ V}, I_C = 75\text{ A}$ $T_{vj} = 25\text{ }^{\circ}\text{C}$	-	1.80	2.35	V
		$V_{GE} = 0\text{ V}, I_C = 75\text{ A}$ $T_{vj} = 175\text{ }^{\circ}\text{C}$	-	1.62	-	
Gate-emitter threshold voltage	V_{GEth}	$V_{CE} = V_{GE}, I_C = 2.6\text{ mA}$ $T_{vj} = 25\text{ }^{\circ}\text{C}$	5.1	5.9	6.6	V
Zero gate voltage collector current	I_{CES}	$V_{CE} = 1200\text{ V}, V_{GE} = 0\text{ V}$ $T_{vj} = 25\text{ }^{\circ}\text{C}$	-	-	40	μA
Gate-emitter leakage current	I_{GES}	$V_{GE} = \pm 20\text{ V}, V_{CE} = 0\text{ V}$	-	-	± 100	nA

Table 5 Dynamic Characteristics

Parameters	Symbol	Conditions	Min	Typ	Max	Unit
Input capacitance	C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$ $f = 1\text{ MHz}$	-	9883	-	pF
Output capacitance	C_{oes}		-	274	-	
Reverse transfer capacitance	C_{res}		-	65	-	
Gate input resistance	R_G	$f = 1\text{ MHz}$	-	0.4	-	Ω
Gate charge	Q_g	$V_{CE} = 600\text{ V}$ $I_C = 75\text{ A}$ $V_{GE} = 0\text{ V to } 15\text{ V}$	-	307	-	nC
Gate to emitter charge	Q_{ge}		-	103	-	
Gate to collector charge	Q_{gc}		-	113	-	



Table 6 Switching Characteristics

Parameters	Symbol	Conditions	Min	Typ	Max	Unit
Turn-on delay time	$t_{d(on)}$	$T_{vj} = 25\text{ }^{\circ}\text{C}$; $V_{CC} = 600\text{ V}$, $I_C = 75\text{ A}$; $V_{GE} = 0 / 15\text{ V}$; $R_g(on) = 5.1\text{ }\Omega$; $R_g(off) = 5.1\text{ }\Omega$;	-	63	-	ns
Rise time	t_r		-	29	-	
Turn-off delay time	$t_{d(off)}$		-	188	-	
Fall time	t_f		-	96	-	
Turn-on energy	E_{on}		-	3.9	-	mJ
Turn-off energy	E_{off}		-	3.0	-	
Total switching energy	E_{ts}		-	6.9	-	
Turn-on delay time	$t_{d(on)}$	$T_{vj} = 175\text{ }^{\circ}\text{C}$; $V_{CC} = 600\text{ V}$, $I_C = 75\text{ A}$; $V_{GE} = 0 / 15\text{ V}$; $R_g(on) = 5.1\text{ }\Omega$; $R_g(off) = 5.1\text{ }\Omega$;	-	48	-	ns
Rise time	t_r		-	27	-	
Turn-off delay time	$t_{d(off)}$		-	262	-	
Fall time	t_f		-	170	-	
Turn-on energy	E_{on}		-	5.38	-	mJ
Turn-off energy	E_{off}		-	4.72	-	
Total switching energy	E_{ts}		-	10.1	-	

Table 7 Diode Recovery Characteristics

Parameters	Symbol	Conditions	Min	Typ	Max	Unit
Reverse recovery time	t_{rr}	$T_{vj} = 25\text{ }^{\circ}\text{C}$; $V_R = 600\text{ V}$, $I_F = 75\text{ A}$; $R_g(on) = 5.1\text{ }\Omega$; $R_g(off) = 5.1\text{ }\Omega$; $di/dt = 2600\text{ A/us}$;	-	366	-	ns
Reverse recovery charge	Q_{rr}		-	7.15	-	μC
Peak reverse recovery current	I_{rrm}		-	57	-	A
Reverse recovery energy	E_{rec}		-	3.10	-	mJ
Reverse recovery time	t_{rr}	$T_{vj} = 175\text{ }^{\circ}\text{C}$; $V_R = 600\text{ V}$, $I_F = 75\text{ A}$; $R_g(on) = 5.1\text{ }\Omega$; $R_g(off) = 5.1\text{ }\Omega$; $di/dt = 2600\text{ A/us}$;	-	511	-	ns
Reverse recovery charge	Q_{rr}		-	18.88	-	μC
Peak reverse recovery current	I_{rrm}		-	122	-	A
Reverse recovery energy	E_{rec}		-	8.44	-	mJ



Electrical Characteristics Diagrams

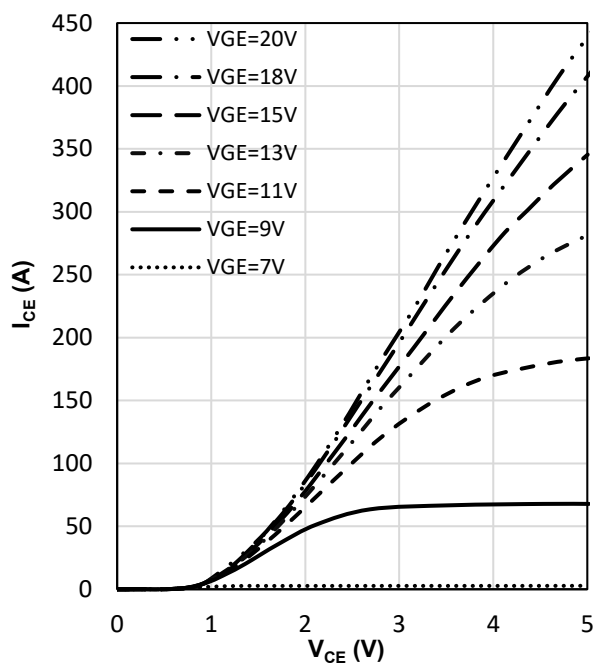


Fig.1 Typical Output Characteristics (25°C)

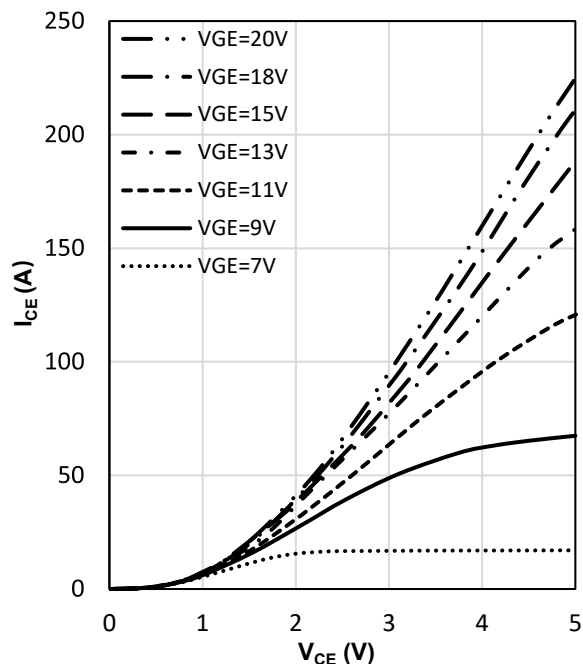


Fig.2 Typical Output Characteristics (175°C)

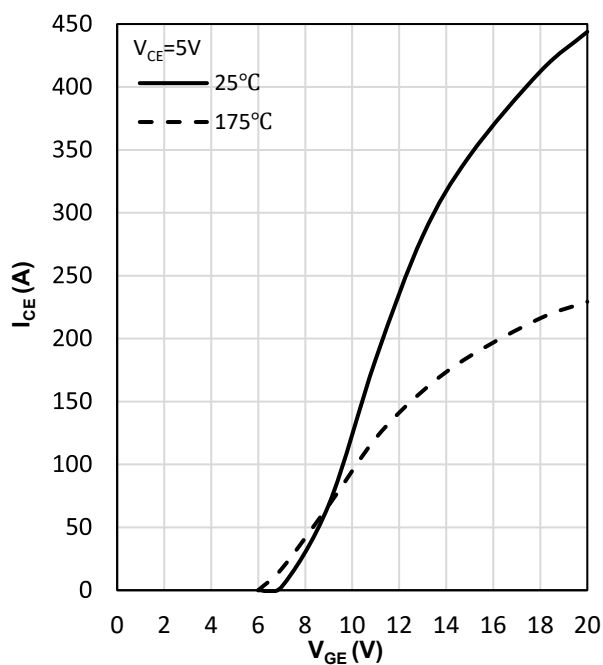


Fig.3 Typical Transfer Characteristics

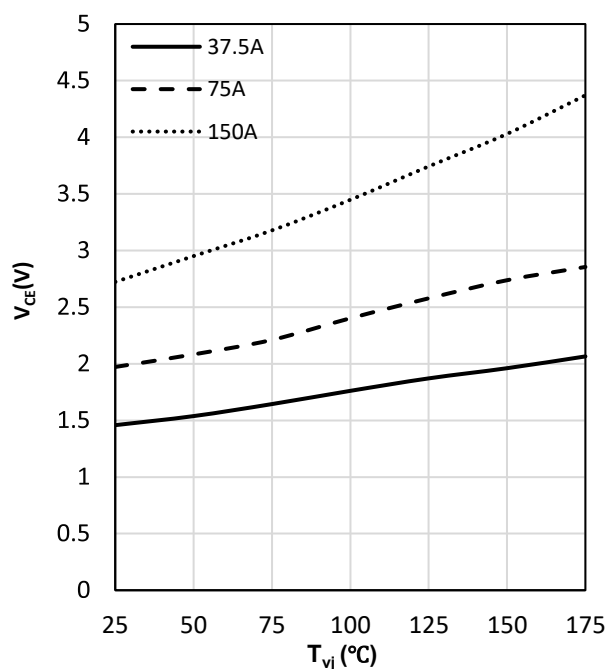


Fig.4 Typical Saturation Voltage

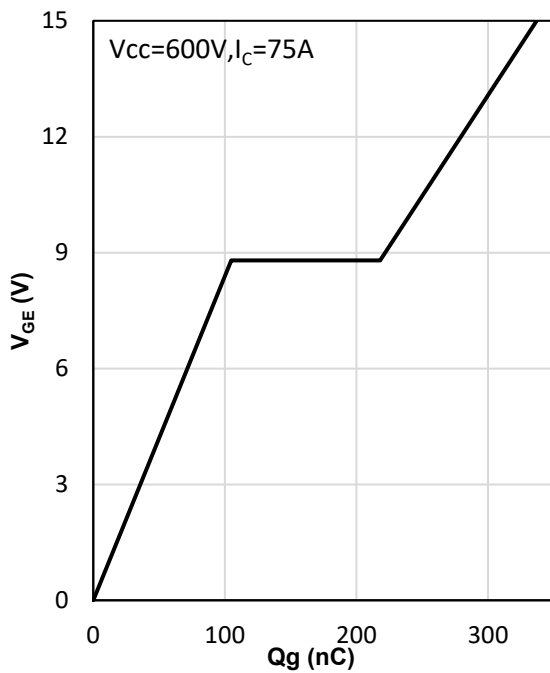


Fig.5 Gate Charge Characteristics

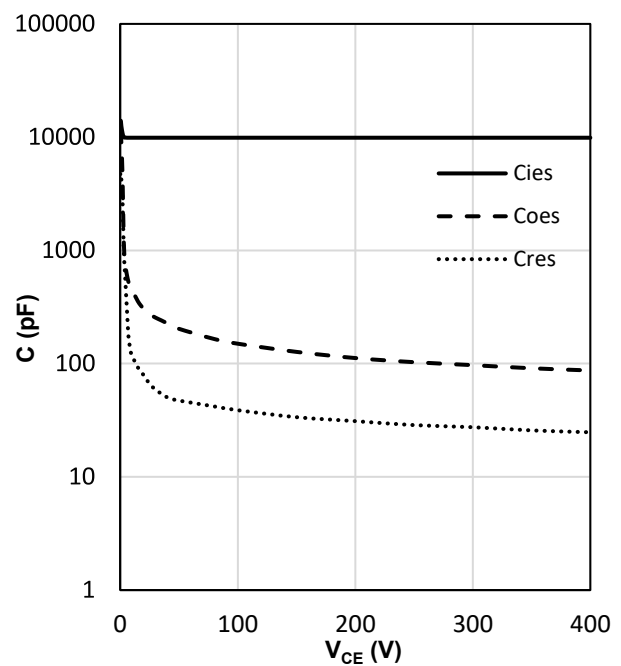


Fig.6 Typical Capacitance

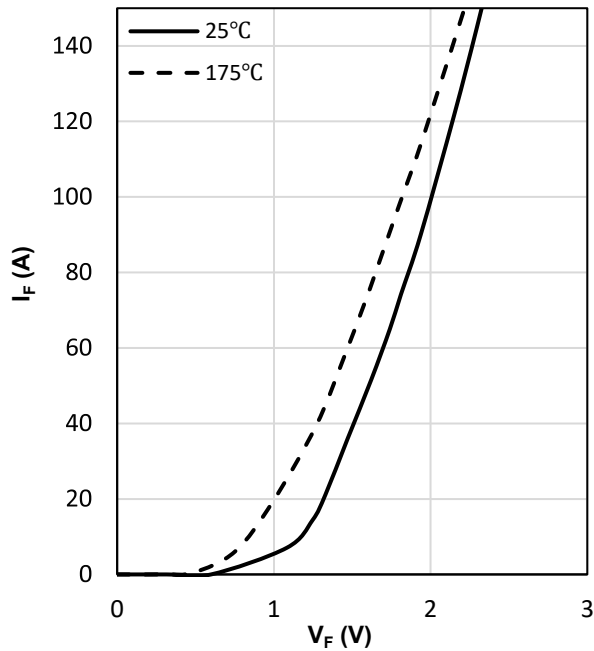


Fig.7 Typical Diode V_F vs. I_F Characteristic

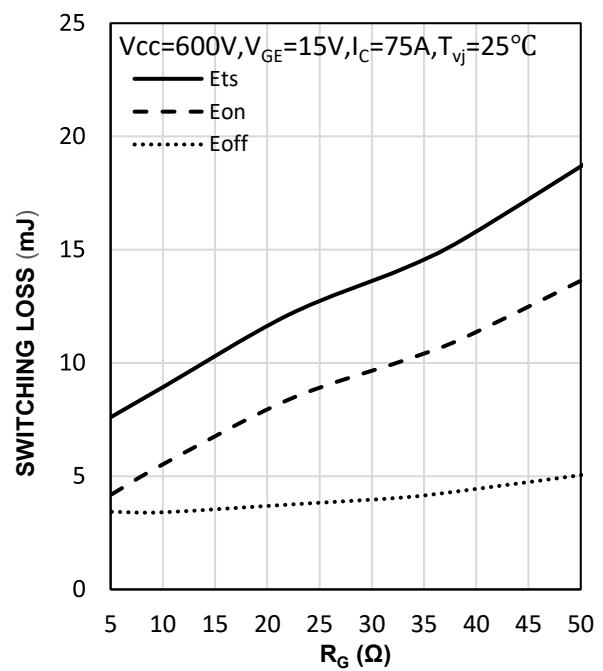


Fig.8 Switching Loss vs. Gate Resistance ($25^\circ C$)

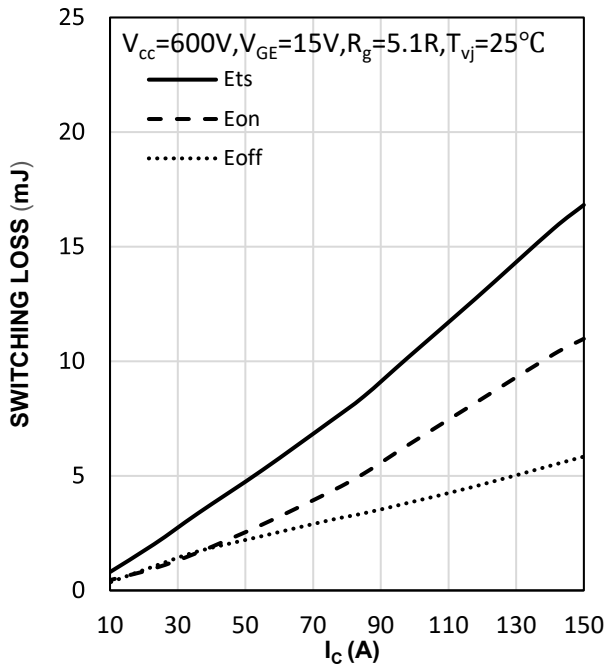


Fig.9 Switching Loss vs. Collector Current(25°C)

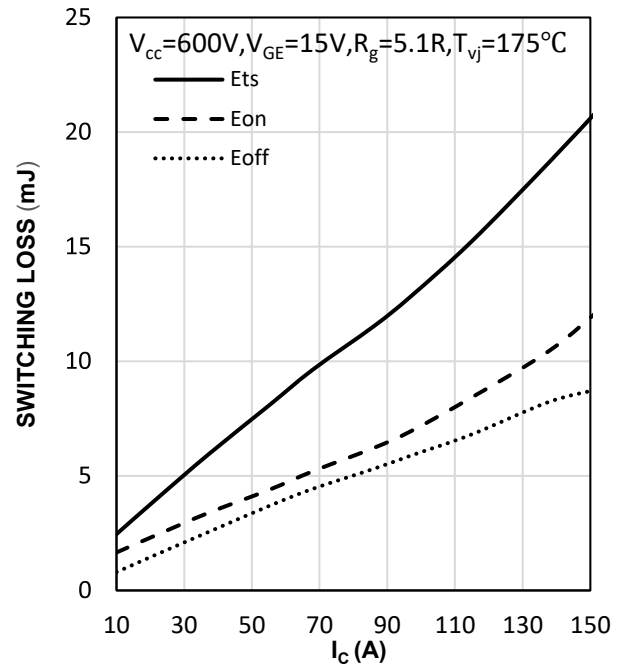


Fig.10 Switching Loss vs. Collector Current(175°C)

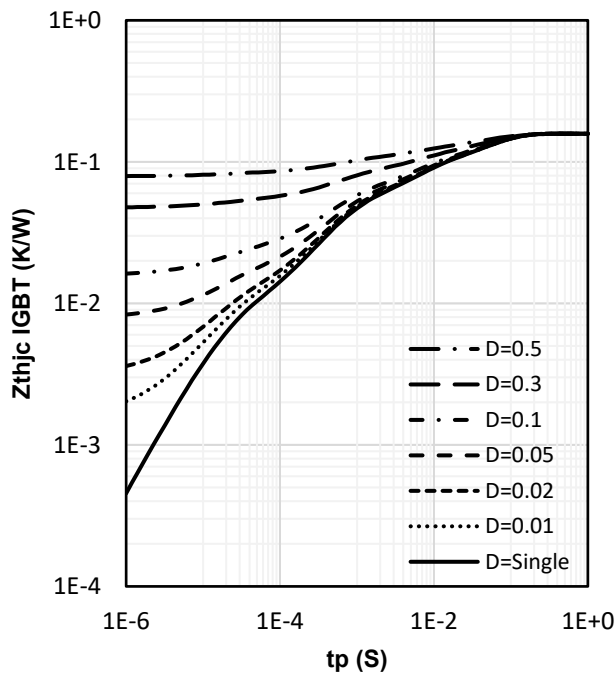


Fig.11 Thermal Characteristics (IGBT)

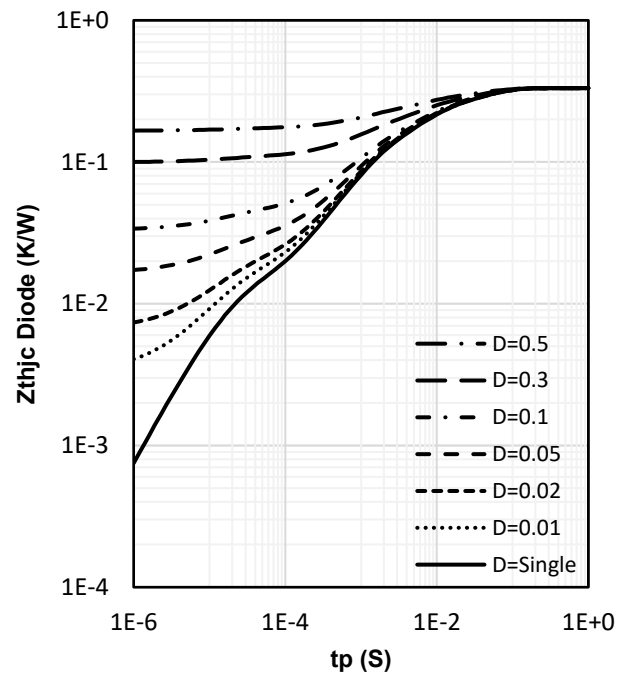
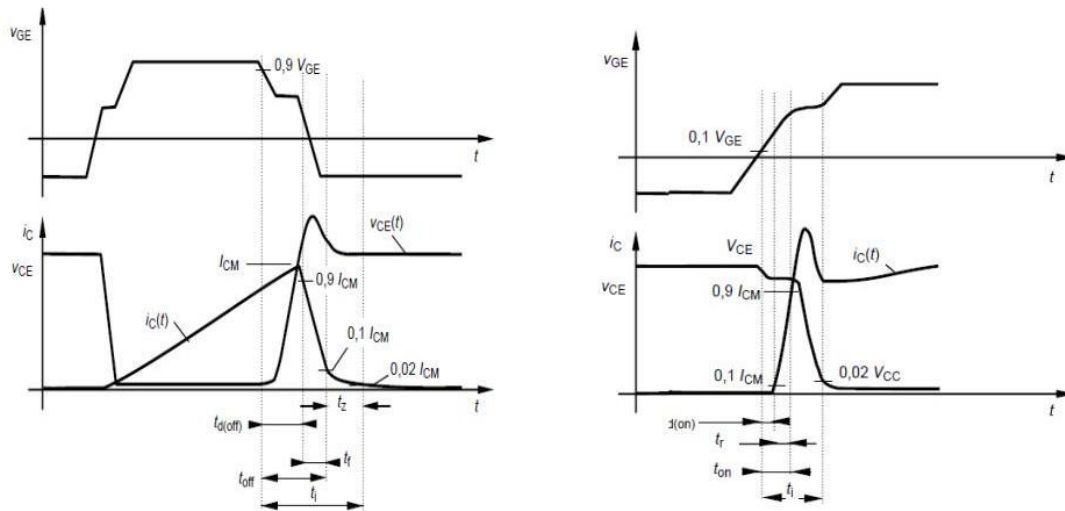


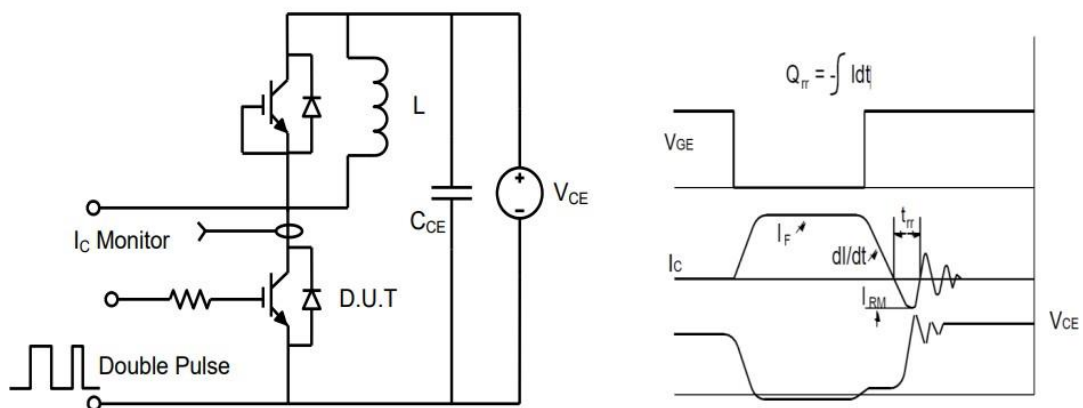
Fig.12 Thermal Characteristics (Diode)



Switching Test Circuit & Waveforms

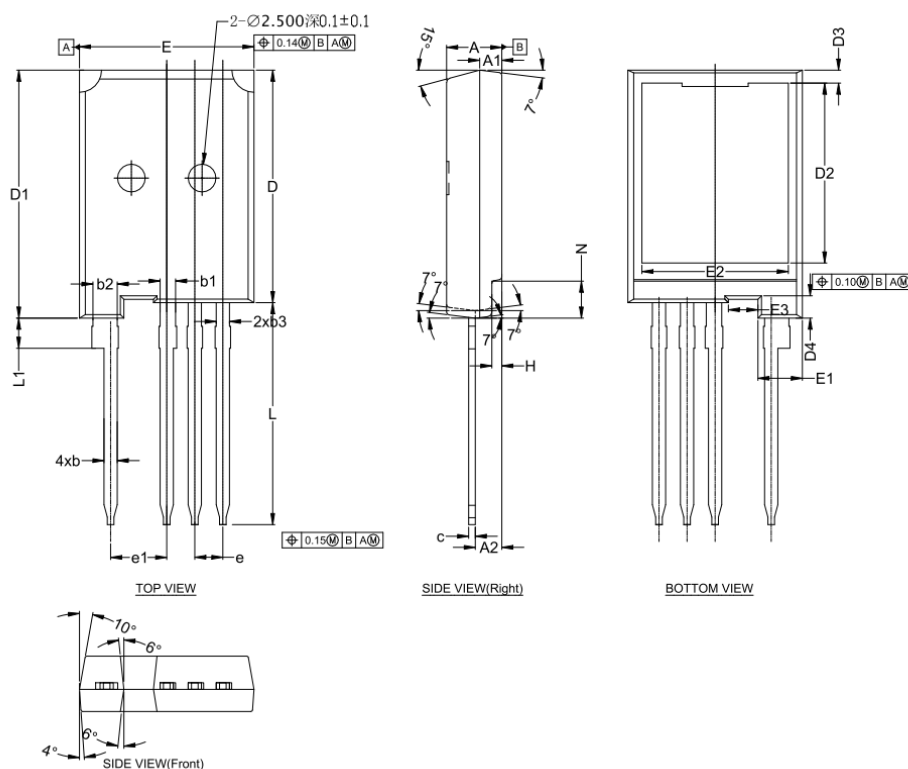


Diode Recovery Test Circuit & Waveforms





Package Outline



DIM SYMBOL	MIN.	NOM.	MAX.
A	4.900	5.000	5.100
A1	1.940	2.040	2.140
A2	2.310	2.400	2.510
b	1.160	1.200	1.290
b1	1.360	1.400	1.490
b2	2.160	2.200	2.290
b3	1.160	1.200	1.390
c	0.590	0.600	0.700
D	20.900	21.000	21.100
D1	22.300	22.400	22.500
D2	15.950	16.250	16.550
D3	0.970	1.170	1.370
D4	1.900	2.000	2.100
E	15.700	15.800	15.900
E1	3.900	4.000	4.100
E2	13.100	13.259	13.500
E3	2.580	2.680	2.780
e	2.540 BSC.		
e1	5.080 BSC.		
L	19.800	20.000	20.100
L1	2.550	2.722	2.850
H	0.800	0.900	1.000
N	3.240	3.340	3.440

NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5-1994
2. ALL DIMENSIONS ARE IN MILLIMETERS, ANGLES ARE IN DEGREE.
3. SURFACE ROUGHNESS:0.8-1.2



Attention

- Any and all HUA XUAN YANG ELECTRONICS products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your HUA XUAN YANG ELECTRONICS representative nearest you before using any HUA XUAN YANG ELECTRONICS products described or contained herein in such applications.
- HUA XUAN YANG ELECTRONICS assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all HUA XUAN YANG ELECTRONICS products described or contained herein.
- Specifications of any and all HUA XUAN YANG ELECTRONICS products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- HUA XUAN YANG ELECTRONICS CO.,LTD. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all HUA XUAN YANG ELECTRONICS products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of HUA XUAN YANG ELECTRONICS CO.,LTD.
- Information (including circuit diagrams and circuit parameters) herein is for example only ; it is not guaranteed for volume production. HUA XUAN YANG ELECTRONICS believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the HUA XUAN YANG ELECTRONICS product that you intend to use.